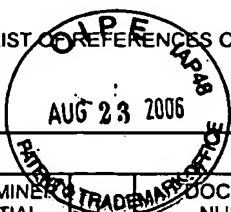


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 268668US26PCT		SERIAL NO. 10/529,191	
LIST OF REFERENCES CITED BY APPLICANT 				APPLICANT Takahiro HORIGUCHI, et al.			
				FILING DATE March 24, 2005		GROUP 2812	
				<b>U.S. PATENT DOCUMENTS</b>			
EXAMINER'S INITIAL	TRADEMARK INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
		AA					
		AB					
		AC					
		AD					
		AE					
		AF					
		AG					
		AH					
		AI					
		AJ					
		AK					
		AL					
		AM					
		AN					
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
/RDI/	AO	3-77315	04/02/1991	Japan (with English Abstract)		X	
/RDI/	AP	10-270436	10/09/1998	Japan (with English Abstract)		X	
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner /Rakesh Dhingra/					Date Considered 06/16/2007		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
268668US26PCTSERIAL NO.  
10/529,191

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT  
Takahiro HORIGUCHI, et al.FILING DATE  
March 24, 2005

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/RD/	AA	5,903,711	05/11/99	OKASE, Wataru			
/RD/	AB	5,904,872	05/18/99	ARAMI, Junichi et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/RD/	AO	09-30893	02/04/97	JP(with English abstract)		NO
/RD/	AP	05-047687	02/26/93	JP(with English abstract)		NO
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

/RD/	AW	Z. H. LU: "SiO <sub>2</sub> film thickness metrology by x-ray photoelectron spectroscopy", Appl. Phys. Lett., Vol. 71, No. 19, November 10, 1997.				
	AX					
	AY					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached

Examiner

/Rakesh Dhingra/

Date Considered

06/16/2007

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.